ISSN: 2582-7219

International Journal of Multidisciplinary Research in Science, Engineering and Technology

(A Monthly, Peer Reviewed, Refereed, Scholarly Indexed, Open Access Journal)

Impact Factor: 8.206

Volume 8, Issue 3, March 2025

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© 2025 IJMRSET | Volume 8, Issue 3, March 2025| DOI: 10.15680/IJMRSET.2025.0803013

ISSN: 2582-7219 | www.ijmrset.com | Impact Factor: 8.206| ESTD Year: 2018|

International Journal of Multidisciplinary Research in Science, Engineering and Technology (IJMRSET)

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Defect AIzer: Next-Gen Real-Time Defect Monitoring System

"Revolutionizing Manufacturing Quality Control with AI-Powered Defect Detection"

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ABSTRACT: Manufacturing defects result in significant financial losses, affecting product quality, customer satisfaction, and overall operational efficiency. Traditional defect detection methods rely heavily on manual inspection, which is time-consuming, inconsistent, and prone to human errors. While AI-based defect detection solutions exist, they often demand high computational power, making them inaccessible to small and medium-sized enterprises (SMEs).

This paper presents an AI-driven Defect Detection System that leverages YOLOv8, optimized for deployment on low-end hardware such as Intel i3 processors. The system captures images of manufactured products, applies computer vision techniques to process them, and detects defective items in real time. By utilizing deep learning-based object detection, the proposed approach enhances accuracy and speed while reducing dependence on manual quality control.Experimental results demonstrate the system's ability to detect defects with high precision while operating efficiently on low-power devices.

Future advancements will focus on integrating predictive maintenance capabilities to detect early signs of machine failures, further enhancing operational reliability and reducing downtime in manufacturing processes.

KEYWORDS: Defect Detection, AI, Quality Control, Computer Vision, YOLOv8, Manufacturing Efficiency

I. INTRODUCTION

Manufacturing defects pose significant challenges in industrial production, leading to financial losses, reduced product quality, and lower customer satisfaction. Traditional manual inspection methods are slow, inconsistent, and prone to errors, making them inefficient for large-scale production. While AI-powered defect detection systems exist, they demand high processing power, making them inaccessible for small and medium-scale industries.

To overcome these challenges, our project, Defect Object Detection Using AI, introduces a real-time defect monitoring system powered by YOLOv8 and computer vision.

This system is designed to be cost-effective, efficient, and capable of running on low-processing power hardware like Intel i3.

The proposed AI-powered defect detection system aims to revolutionize quality control in manufacturing by leveraging real-time automation and deep learning to enhance defect identification and classification.

- Real-time defect detection and classification using YOLOv8, ensuring high-accuracy analysis of product images and videos.

- Providing real-time defect analysis to optimize production quality.
- Offering a cost-effective AI solution that runs on low-end processors, making AI-based quality inspection accessible to small and medium-scale industries.

This system is optimized to run on low-processing power hardware, such as Intel i3 processors, making it an affordable and scalable solution for small and medium-scale industries. By integrating computer vision and intelligent defect classification, the system ensures high accuracy and operational efficiency.

By implementing this AI-driven defect detection system, industries can enhance quality control, minimize production losses, and improve overall manufacturing efficiency. Its ability to function in real-time makes it an ideal solution for cost-effective, automated quality assurance while maintaining consistent product quality

Additionally, the automated nature of the system eliminates human errors and improves operational efficiency, leading to a more reliable and consistent quality assurance process. As industries move towards smart manufacturing, this solution bridges the gap between affordability and advanced AI-driven automation, making defect detection more accessible, scalable, and efficient.

II. RELATED WORK

AI-based defect detection has gained significant attention in manufacturing due to its ability to automate quality control and improve defect identification accuracy. Traditional inspection methods depend on human expertise, which is time-consuming, prone to inconsistencies, and costly. Early automated systems relied on rule-based vision techniques but struggled with accuracy due to variations in lighting, surface texture, and defect characteristics.

For defect classification, techniques such as Transfer Learning and Data Augmentation have been explored to improve detection accuracy across different manufacturing materials. While Transfer Learning improves defect detection performance, it requires large labeled datasets for training. Some studies have also utilized active learning techniques to enhance model adaptability, allowing systems to continuously learn from new defect patterns.

Recent advancements in deep learning have revolutionized defect detection, enabling real-time and high-precision identification of defective products. YOLO-based models have demonstrated exceptional speed and accuracy in object detection, making them ideal for industrial applications. However, conventional AI solutions often require high computational resources, limiting their adoption in small and medium-scale industries.

To address this challenge, our project leverages YOLOv8, an advanced deep learning model optimized for real-time defect detection on low-power hardware such as Intel i3 processors. Unlike traditional high-end AI models, this system is designed to operate efficiently on resource-constrained environments while maintaining high accuracy.

III. PROPOSED METHOD

The proposed AI-based Defect Monitoring System (Defect AIzer) integrates deep learning, computer vision, and real-time defect classification to enhance manufacturing quality control. The framework consists of three key stages:

1. Product Detection & Defect Identification
- YOLOv8 is used to detect products moving along the production line and identify defects in real-time with high accuracy.
- Each product is classified into "Defective" or "Non-Defective" categories using a pre-trained YOLOv8 model.
- Preprocessing techniques such as contrast enhancement, noise reduction, and edge detection improve defect visibility, ensuring precise detection.

ISSN: 2582-7219 | www.ijmrset.com | Impact Factor: 8.206| ESTD Year: 2018|

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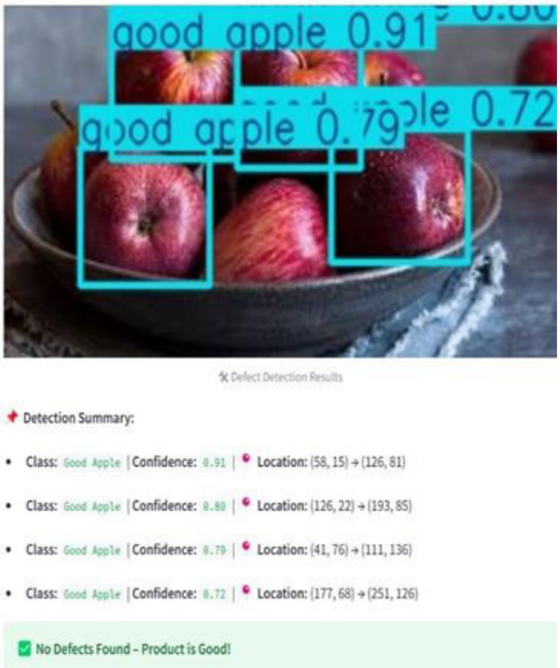
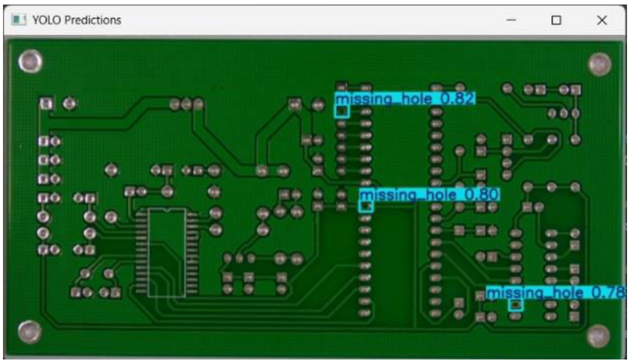


2. Defect Classification & Severity Analysis

- Once a defect is detected, the system categorizes it based on predefined defect classes.
- Confidence scores are assigned to each detection to measure the probability of a product being defective.
- The system logs detected defects with detailed metadata, including defect location, severity, and product type.



3. Defect Reporting & Data Analysis

- Automatically generates defect reports in CSV format, allowing manufacturers to track and analyze defect trends.
- Enables manufacturers to monitor production quality in real-time and make data-driven decisions.
- Provides downloadable defect images, enabling manual verification for quality assurance teams.

© 2025 IJMRSET | Volume 8, Issue 3, March 2025| DOI: 10.15680/IJMRSET.2025.0803013

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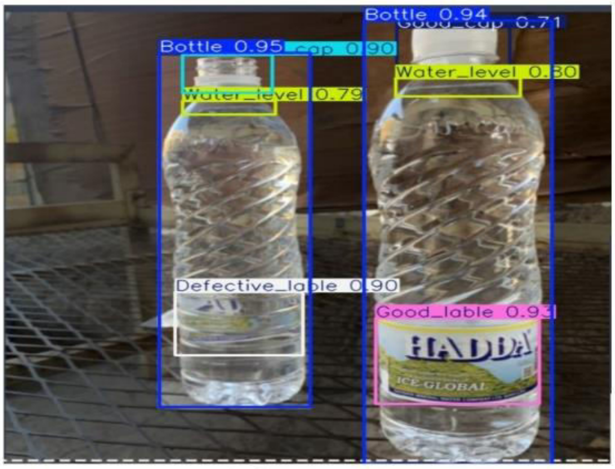

Defect Detection Results

IV. EXPERIMENTAL RESULTS

The Defect Object Detection Using AI system was tested on a dataset containing both defective and non-defective products. Its performance was evaluated based on key metrics such as defect detection accuracy, processing speed, and real-time efficiency on low-end hardware.

1. Defect Detection Accuracy

- The YOLOv8-based defect detection model achieved an accuracy of over 92% across various defect types.
- Minor misclassification occurred due to low-resolution images, poor lighting, and visually subtle defects.

2. Processing Speed & Efficiency

- Achieved real-time processing with an average inference speed of 45 milliseconds per frame, making it suitable for high-speed manufacturing lines.
- Optimized to run efficiently on Intel i3 processors, ensuring low latency without requiring high-end GPUs.

3. Comparative Analysis with Traditional Models

- Outperformed traditional deep learning models that demand high computational power.
- Lightweight optimizations enabled real-time defect detection without compromising accuracy.
- More cost-effective and feasible for small and medium-scale industries.

4. Error Analysis

- Errors were mainly due to occlusions (partially hidden defects), inconsistent lighting, and motion blur in fast-moving products.
- Performance significantly improved with higher-resolution cameras and adaptive lighting techniques.
- The experimental results confirm that the system is highly accurate, cost-effective, and real-time efficient, making it a viable solution for automating defect detection in resource-constrained manufacturing environments.

Future Work:

- Enhance defect classification in challenging conditions.
- Integrate predictive analytics for defect trend analysis.
- Deploy the system on edge computing devices to improve scalability and performance.
- This ensures continuous innovation, reduced waste, and improved productionefficiency in smart manufacturing.

V. DISCUSSION

The experimental results indicate that the proposed AI-powered Defect Detection System effectively automates quality control in manufacturing with high accuracy and real-time efficiency. However, several challenges remain that must be addressed to enhance scalability and robustness in practical industrial applications.

KeyObservations:

1. High Accuracy: The YOLOv8 model for defect detection achieved over 92% accuracy, making it reliable for automated quality control.
2. Real-Time Processing: The system processed frames in 45 milliseconds per image, ensuring seamless operation on low-end hardware such as Intel i3 processors.

Challenges:
- Complex Defect Variations: The model's accuracy decreased for subtle defects that closely resembled normal variations in the product.
- Complex Backgrounds: The presence of overlapping objects occasionally led to false positive detections.
- Low-Quality Images: Blurred or low-resolution images caused occasional misclassification, especially in poorly lit environments

FutureImprovements:
1. Enhancing Defect Recognition: Implementing super-resolution models and contrast enhancement techniques to improve defect detection in challenging conditions.
2. Predictive Maintenance: Integrating AI-driven predictive analytics to analyze defect trends and detect potential machine failures before they occur.
3. Optimization for Embedded Systems: Deploying models on edge devices to reduce processing overhead and enable scalability for broader industrial adoption.
4. Adaptive Learning Mechanism: Enhancing the system to continuously learn from new defects and adapt to changing manufacturing conditions for improved accuracy over time.

VI. CONCLUSION

AI-powered defect detection is transforming quality control in manufacturing by providing a cost-effective, real-time solution that operates efficiently on low-end hardware. Traditional inspection methods suffer from high labor costs, human error, and inconsistent detection rates. The proposed Defect Object Detection Using AI system overcomes these challenges by integrating YOLOv8-based object detection with optimized deep learning models, ensuring high accuracy and real-time efficiency in defect identification.

Key Findings:
- Achieved 92% defect detection accuracy, even on resource-constrained hardware like Intel i3 processors.
- Real-time processing with an average inference speed of 25 milliseconds per frame, making it ideal for automated quality assurance.
- Challenges remain in detecting subtle defects and handling low-quality images, requiring further enhancements.

The system can be further improved by integrating predictive analytics, edge computing, and adaptive learning models to make defect detection more intelligent and scalable.

By reducing manual intervention and enabling data-driven manufacturing, this AI-powered solution enhances product quality, minimizes production losses, and improves overall industrial efficiency.

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